PATENT

DK-US065116

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Junko TAKAHASHI et al.

Serial No.: New – (National Phase of

PCT/JP2004/017779)

International filing date: November 30, 2004

For: METHOD OF EXAMINING CHEMICAL USING GENE-DISRUPTED STRAIN

INFORMATION DISCLOSURE STATEMENT

Assistant Commissioner of Patents Washington, DC 20231

Sir:

In accordance with MPEP 609 and 37 C.F.R. §§ 1.56, 1.97 and 1.98, Applicants bring the references listed on the attached PTO-1449-Form to the Examiner's attention and request that they be considered and made of record in this application. Copies of the non-U.S. patents are attached.

Prompt examination on the merits is respectfully requested.

Respectfully submitted,

David L. Tarnoff Reg. No. 32,383

GLOBAL IP COUNSELORS, LLP 1233 Twentieth Street, NW, Suite 700 Washington, DC 20036 (202)-293-0444

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Dated: 3-31-66

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10/581U85 AP3 Rec'd PCT/PTO 31 MAY 2000

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Substitute for form 1449A/PTO

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

Application Number PCT/JP2004/017779

Filing Date International Date of November 30, 2004

First Named Inventor Junko TAKAHASHI

Group Art Unit

Examiner Name

Attorney Docket Number DK-US065116

(use as many sheets as necessary)
Sheet 1 of 1

U.S. PATENT DOCUMENTS Name of Patentee or Applicant of Document Number Pages, Columns, Lines, Where Relevant **Publication Date** Cited Document Examiner Cite No.1 MM-DD-YYYY Passages or Relevant Initials 1 Number - Kind Code² (if known) Figures Appear US- 2004-0248126-A1 12-09-2004 Iwahashi et al. US- 2005-0112573-A1 05-26-2005 lwahashi et al. US-US-US-US-US-US-US-US-US-US-US-US-US-US-US-US-US-บร-

Examiner Initials*	Cite No.1	Foreign Patent Document		Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T⁵
		Country Code ³ - Number ⁴ - Kind Code ⁵ (<i>if known</i>)	Publication Date MM-DD-YYYY			
		JP-2001-095596-A	04-10-2001	lwama	Abstract Only	Yes
		JP-2001-238694-A	09-04-2001	lwahashi et al.		Yes
		JP-2001-286281-A	10-16-2001	lwahashi et al.		Yes
		WO-03-018791-A1	03-06-2003	lwahashi et al.		Yes
		WO-03-018792-A1	03-06-2003	lwahashi et al.		Yes

Examiner Signature	/James Martinell/	Date Considered	09/18/2010

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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¹ Applicant's unique citation designation number (optional). ² See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.